

Notice of References Cited

Application/Control No.

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Applicant(s)/Patent Under
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LIN, WENHUA

Examiner

Krystyna Suchecki

Art Unit

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-			
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	D	US-			
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	F	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Nowak, E.D. "Speed Power, and Yield Comparison of Thin Bonded sOI versus Bulk CMOS Technologies" Proceedings 1994 IEEE International SOI Conference, Oct. 1994
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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